


<b>Search Notes</b>  	<b>Application/Control No.</b>  10554231	<b>Applicant(s)/Patent Under Reexamination</b>  BJORKLUND ET AL.
	<b>Examiner</b>  SHEELA C CHAWAN	<b>Art Unit</b>  2624

SEARCHED			
Class	Subclass	Date	Examiner
382	188, 179, 181, 305, 173,	11/24/08	SCC
358	473, 406, 401, 402	"	"
345	156, 157, 103, 104, 164, 165, 167, 173, 179, 162	"	"
178	18.01, 18.09	"	"
235	494	"	"
382	181	5/16/09	SCC
178	18.01	5/16/09	SCC
345	103, 162	5/16/09	SCC
235	494	5/16/09	SCC
ABOVE SEARCH UP- DARE		5/16/09	SCC
382	181	9/24/09	SCC
178	18.01	9/24/09	SCC
345	103,162	9/24/09	SCC
235	494	9/24/09	SCC
ABOVE SEARCH UP- DATE		9/24/09	SCC

SEARCH NOTES		
Search Notes	Date	Examiner
SEARCH EAST AND OTHER DATA BASE.	11/24/08	SCC
SEARCH INVENTOR NAME SEARCH.	"	"
SEARCH EAST AND OTHER DATA BASE, SEE THE SEARCH HISTORY.	5/16/09	SCC
SEARCH 382/ 188,179,181,305,173.ccls. US-PATENT ONLY TEXT SEARCH.	5/16/09	SCC
345/156,175,157,103,104,164,165,173,179.CCLS. "	5/16/09	SCC
178/18.09,18.01.ccls. "	5/16/09	SCC
235/494.ccls. "	5/16/09	SCC
INTERFERENCE SEARCH	5/16/09	SCC
SEARCH IEEE OR INSPEC	5/16/09	SCC

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<b>SEARCH NOTES</b>		
<b>Search Notes</b>	<b>Date</b>	<b>Examiner</b>
ABOVE SEARCH UP-DATE	5/16/09	SCC
SEARCH UPDATE.	9/24/09	SCC

<b>INTERFERENCE SEARCH</b>			
<b>Class</b>	<b>Subclass</b>	<b>Date</b>	<b>Examiner</b>
382	181, 188	5/16/09	SCC
178	18.01	5/16/09	SCC
235	494	5/16/09	SCC
345	103, 162	5/16/09	SCC